

	Type	Hits	Search Text	DBs
1	BRS	3431	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	124700 2	semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	BRS	855	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region)) and semiconductor and @ad<=20000419	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	BRS	551	(determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near9 (semiconductor near3 die)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	32	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 die)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	BRS	23	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 die) and @ad<=20000419	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	1	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region)) and ((determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near9 (semiconductor near3 die))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
8	BRS	14	((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region)) and semiconductor and @ad<=20000419 and ((semiconductor or wafer) near2 die\$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	IS&R	12	((5,056,061") or ("5,553,022") or ("5,642,307") or ("4,419,747") or ("5,056,061") or ("4,766,516")).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	IS&R	2	("5,350,715").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Type	Hits	Search Text	DBs
11	BRS	1	((("5,056,061") or ("5,553,022") or ("5,642,307") or ("4,419,747") or ("5,056,061") or ("4,766,516")).PN.) and (((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or chang\$5 or alter\$5) or disturb\$5 or modif\$7 or inspect\$5) near5 (die or area or region)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	BRS	57321	(determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near5 semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
13	BRS	103	((((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))) and ((determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near5 semiconductor) and @ad<=20000419	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
14	BRS	59	((((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))) and ((determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near5 semiconductor) and @ad<=20000419) not (semiconductor adj laser)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB